BF1216

Dual N-channel dual gate MOSFET

Rev. 01 — 29 April 2010

Product data sheet

1. Product profile

1.1 General description

The BF1216 is a combination of two dual gate MOSFET amplifiers with shared source and gate2 leads.

The source and substrate are interconnected. Internal bias circuits enable DC stabilization and very good cross modulation performance during AGC. Integrated diodes between the gates and source protect against excessive input voltage surges. The transistor is available as a SOT363 micro-miniature plastic package.

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Therefore care should be taken during transport and handling.

1.2 Features and benefits

- Two low noise gain controlled amplifiers in a single package; both with a partly integrated bias
- Superior cross modulation performance during AGC
- High forward transfer admittance
- High forward transfer admittance to input capacitance ratio

1.3 Applications

- Gain controlled low noise amplifiers for VHF and UHF applications running on a 5 V supply voltage
 - digital and analog television tuners
 - professional communication equipment



Dual N-channel dual gate MOSFET

1.4 Quick reference data

Table 1. Quick reference data for amplifier A and B

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V_{DS}	drain-source voltage	DC		-	-	6	V
I_D	drain current	DC		-	-	30	mA
P_{tot}	total power dissipation	$T_{sp} \le 107 ^{\circ}C$	[1]	-	-	180	mW
y _{fs}	forward transfer admittance	f = 100 MHz; T_j = 25 °C; I_D = 18 mA		23	27	38	mS
C _{iss(G1)}	input capacitance at gate1	f = 100 MHz	[2]	-	2.5	-	pF
C _{rss}	reverse transfer capacitance	f = 100 MHz	[2]	-	25	-	fF
NF	noise figure	$f = 400 \text{ MHz}; Y_S = Y_{S(opt)}$		-	1.0	-	dB
		$f = 800 \text{ MHz}; Y_S = Y_{S(opt)}$		-	1.5	-	dB
Xmod	cross modulation	input level for k = 1 % at 40 dB AGC; f_w = 50 MHz; f_{unw} = 60 MHz	[3]	105	107	-	dBμV
Tj	junction temperature			-	-	150	°C
·							· ·

^[1] T_{sp} is the temperature at the soldering point of the source lead.

2. Pinning information

Table 2. Discrete pinning

Pin	Description	Simplified outline	Graphic symbol
1	gate1 (amplifier A)		
2	gate2	6 5 4	AMP A
3	gate1 (amplifier B)		G1A DA
4	drain (amplifier B)	0	G2 + S
5	source	□1 □2 □3	
6	drain (amplifier A)		G1B DB AMP B sym119

3. Ordering information

Table 3. Ordering information

Type number	Package					
	Name	Description	Version			
BF1216	-	plastic surface-mounted package; 6 leads	SOT363			

Product data sheet

^[2] Calculated from S-parameters.

^[3] Measured in Figure 17 test circuit.

Dual N-channel dual gate MOSFET

4. Marking

Table 4. Marking

•		
Type number	Marking	Description
BF1216	М5р	made in Hong Kong
	M5t	made in Malaysia
	M5w	made in China

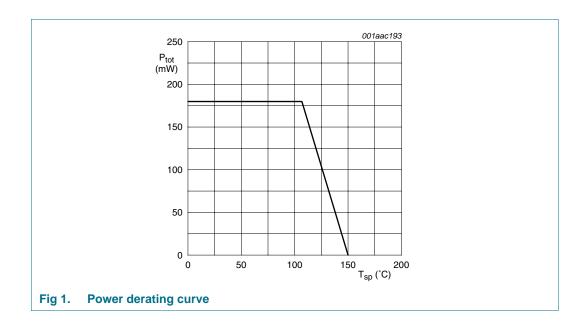
5. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
Per MOSF	ET				
V _{DS}	drain-source voltage		-	6	V
I _D	drain current	DC	-	30	mA
I _{G1}	gate1 current		-	±10	mA
I _{G2}	gate2 current		-	±10	mA
P _{tot}	total power dissipation	$T_{sp} \leq 107~^{\circ}C$	[1] -	180	mW
T _{stg}	storage temperature		-65	+150	°C
Tj	junction temperature		-	150	°C

^[1] T_{sp} is the temperature at the soldering point of the source lead.



Dual N-channel dual gate MOSFET

6. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Тур	Unit
$R_{th(j-sp)}$	thermal resistance from junction to solder point		240	K/W

7. Static characteristics

Table 7. Static characteristics

 $T_i = 25 \, {}^{\circ}\text{C}.$

Symbol	Parameter	Conditions	N	/lin	Тур	Max	Unit
Per MOSF	ET; unless otherwise specified						
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{G1-S} = V_{G2-S} = 0 \text{ V}; I_D = 10 \mu\text{A}$					
		amplifier A	6	;	-	-	V
		amplifier B	6	;	-	-	V
V _{(BR)G1-SS}	gate1-source breakdown voltage	$V_{G2-S} = V_{DS} = 0 \text{ V}; I_{G1-S} = 10 \text{ mA}$	6	;	-	10	V
V _{(BR)G2-SS}	gate2-source breakdown voltage	$V_{G1-S} = V_{DS} = 0 \text{ V}; I_{G2-S} = 10 \text{ mA}$	6	;	-	10	V
V _{F(S-G1)}	forward source-gate1 voltage	$V_{G2-S} = V_{DS} = 0 \text{ V}; I_{S-G1} = 10 \text{ mA}$	C	.5	-	1.5	V
V _{F(S-G2)}	forward source-gate2 voltage	$V_{G1-S} = V_{DS} = 0 \text{ V}; I_{S-G2} = 10 \text{ mA}$	C	.5	-	1.5	V
V _{G1-S(th)}	gate1-source threshold voltage	$V_{DS} = 5 \text{ V}; V_{G2-S} = 4 \text{ V}; I_D = 100 \mu\text{A}$	C	.3	-	1.0	V
V _{G2-S(th)}	gate2-source threshold voltage	$V_{DS} = 5 \text{ V}; V_{G1-S} = 5 \text{ V}; I_D = 100 \mu\text{A}$	C	.4	-	1.0	V
I _{DS}	drain-source current	$V_{G2-S} = 4 V$	<u>[1]</u>				
		amplifier A; $V_{DS(A)} = 5 \text{ V}$; $R_{G1(A)} = 39 \text{ k}\Omega$	-		-	24	mΑ
		amplifier B; $V_{DS(B)} = 5 \text{ V}$; $R_{G1(B)} = 39 \text{ k}\Omega$	-		-	24	mΑ
I _{G1-S}	gate1 cut-off current	$V_{G2-S} = 0 \text{ V}; V_{DS(A)} = V_{DS(B)} = 0 \text{ V}$					
		amplifier A; V _{G1-S(A)} = 5 V	-		-	50	nΑ
		amplifier B; $V_{G1-S(B)} = 5 \text{ V}$	-		-	50	nΑ
I _{G2-S}	gate2 cut-off current	$V_{G2-S} = 4 \text{ V}; V_{DS(A)} = V_{DS(B)} = 0 \text{ V};$ $V_{G1-S(A)} = V_{G1-S(B)} = 0 \text{ V}$	-		-	20	nA

^[1] R_{G1} connects gate1 to V_{GG} = 5 V; see <u>Figure 17</u>.

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8. Dynamic characteristics

Table 8. Dynamic characteristics for amplifier A and B

Common source; $T_{amb} = 25$ °C; $V_{G2-S} = 4$ V; $V_{DS} = 5$ V; $I_D = 19$ mA.

Symbol	Parameter	Conditions		Min	Tyrs	Max	Unit
•						Max	
y _{fs}	forward transfer admittance	$f = 100 \text{ MHz}; T_j = 25 ^{\circ}\text{C}; I_D = 18 \text{ mA}$		23	27	38	mS
$C_{\text{iss}(G1)}$	input capacitance at gate1	f = 100 MHz	[1]	-	2.5	-	pF
$C_{iss(G2)}$	input capacitance at gate2	f = 100 MHz	[1]	-	2.4	-	pF
Coss	output capacitance	f = 100 MHz	[1]	-	8.0	-	pF
C _{rss}	reverse transfer capacitance	f = 100 MHz	[1]	-	25	-	fF
G _{tr}	transducer power gain	amplifier A; $B_S = B_{S(opt)}$; $B_L = B_{L(opt)}$	[1]				
		$f = 200 \text{ MHz}; G_S = 2 \text{ mS}; G_L = 0.5 \text{ mS}$		-	34	-	dB
		$f = 400 \text{ MHz}; G_S = 2 \text{ mS}; G_L = 1 \text{ mS}$		-	30	-	dB
		$f = 800 \text{ MHz}$; $G_S = 3.3 \text{ mS}$; $G_L = 1 \text{ mS}$		-	26	-	dB
		amplifier B; $B_S = B_{S(opt)}$; $B_L = B_{L(opt)}$	[1]				
		$f = 200 \text{ MHz}; G_S = 2 \text{ mS}; G_L = 0.5 \text{ mS}$		-	34	-	dB
		$f = 400 \text{ MHz}; G_S = 2 \text{ mS}; G_L = 1 \text{ mS}$		-	30	-	dB
		$f = 800 \text{ MHz}; G_S = 3.3 \text{ mS}; G_L = 1 \text{ mS}$		-	26	-	dB
NF	noise figure	$f = 11 \text{ MHz}; G_S = 20 \text{ mS}; B_S = 0 \text{ S}$		-	-	5	dB
		$f = 400 \text{ MHz}; Y_S = Y_{S(opt)}$		-	1.0	-	dB
		$f = 800 \text{ MHz}; Y_S = Y_{S(opt)}$		-	1.5	-	dB
Xmod	cross modulation	input level for k = 1 % at 40 dB AGC; f_w = 50 MHz; f_{unw} = 60 MHz	[2]				
		at 0 dB AGC		90	104	-	$dB\mu V \\$
		at 10 dB AGC		-	100	-	$dB\mu V$
		at 20 dB AGC		-	104	-	$dB\mu V$
		at 40 dB AGC		105	107	-	dBμV

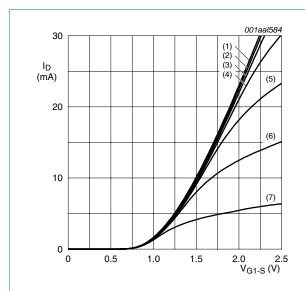
^[1] Calculated from S-parameters.

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^[2] Measured in Figure 17 test circuit.

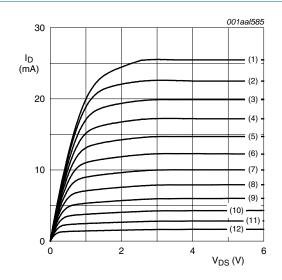
Dual N-channel dual gate MOSFET

8.1 Graphs for amplifiers A and B



- (1) $V_{G2-S} = 4.0 \text{ V}.$
- (2) $V_{G2-S} = 3.5 \text{ V}.$
- (3) $V_{G2-S} = 3.0 \text{ V}.$
- (4) $V_{G2-S} = 2.5 \text{ V}.$
- (5) $V_{G2-S} = 2.0 \text{ V}.$
- (6) $V_{G2-S} = 1.5 \text{ V}.$
- (7) $V_{G2-S} = 1.0 \text{ V}.$

 $V_{DS} = 5 \text{ V}; T_j = 25 \text{ }^{\circ}\text{C}.$

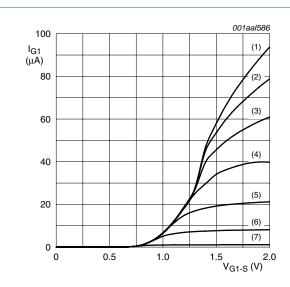


- (1) $V_{G1-S} = 2.1 \text{ V}.$
- (2) $V_{G1-S} = 2.0 \text{ V}.$
- (3) $V_{G1-S} = 1.9 \text{ V}.$
- (4) $V_{G1-S} = 1.8 \text{ V}.$
- (5) $V_{G1-S} = 1.7 \text{ V}.$
- (6) $V_{G1-S} = 1.6 \text{ V}.$
- (7) $V_{G1-S} = 1.5 \text{ V}$. (8) $V_{G1-S} = 1.4 \text{ V}$.
- (9) $V_{G1-S} = 1.3 \text{ V}.$
- (10) $V_{G1-S} = 1.2 \text{ V}.$
- (11) $V_{G1-S} = 1.1 \text{ V}.$
- (12) $V_{G1-S} = 1.0 \text{ V}.$ $V_{G2-S} = 4 \text{ V}; T_j = 25 \,^{\circ}\text{C}.$

Fig 3. Output characteristics; typical values

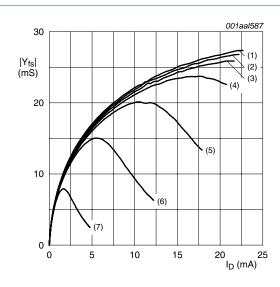
Fig 2. Transfer characteristics; typical values

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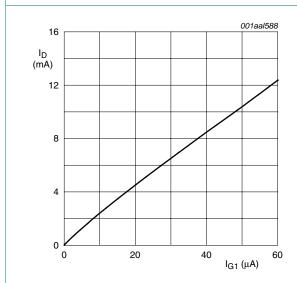
- (1) $V_{G2-S} = 4.0 \text{ V}.$
- (2) $V_{G2-S} = 3.5 \text{ V}.$
- (3) $V_{G2-S} = 3.0 \text{ V}.$
- (4) $V_{G2-S} = 2.5 \text{ V}.$
- (5) $V_{G2-S} = 2.0 \text{ V}.$
- (6) $V_{G2-S} = 1.5 \text{ V}.$
- (7) $V_{G2-S} = 1.0 \text{ V}.$ $V_{DS} = 5 \text{ V}; T_i = 25 \text{ }^{\circ}\text{C}.$

Fig 4. Gate1 current as a function of gate1 voltage; typical values



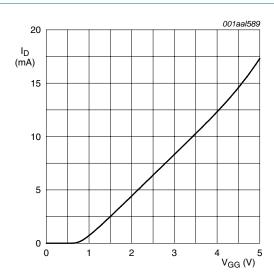
- (1) $V_{G2-S} = 4.0 \text{ V}.$
- (2) $V_{G2-S} = 3.5 \text{ V}.$
- (3) $V_{G2-S} = 3.0 \text{ V}.$
- (4) $V_{G2-S} = 2.5 \text{ V}.$
- (5) $V_{G2-S} = 2.0 \text{ V}.$
- (6) $V_{G2-S} = 1.5 \text{ V}.$
- (7) $V_{G2-S} = 1.0 \text{ V}.$
 - $V_{DS} = 5 \text{ V}; T_i = 25 \text{ }^{\circ}\text{C}.$

Fig 5. Forward transfer admittance as a function of drain current; typical values



 $V_{DS} = 5 \text{ V}; V_{G2-S} = 4 \text{ V}; T_j = 25 \text{ °C}.$

Fig 6. Drain current as a function of gate1 current; typical values

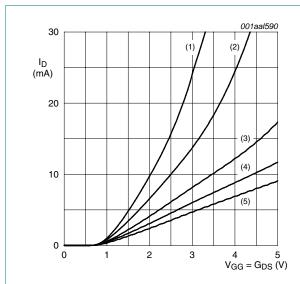


 V_{DS} = 5 V; $V_{G2\text{-}S}$ = 4 V; R_{G1} = 39 kΩ; T_{j} = 25 °C.

Fig 7. Drain current as a function of gate1 supply voltage (V_{GG}); typical values

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Dual N-channel dual gate MOSFET



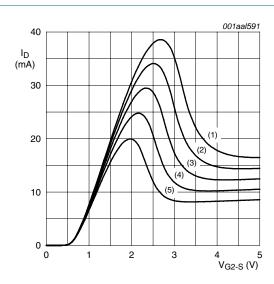
- (3) $R_{G1} = 40 \text{ k}\Omega$.
- (4) $R_{G1} = 60 \text{ k}\Omega$.
- (5) $R_{G1} = 80 \text{ k}\Omega$.

typical values

Fig 8. Drain current as a function of V_{DS} and V_{GG} ;

(1) $R_{G1} = 10 \text{ k}\Omega$. (2) $R_{G1} = 20 \text{ k}\Omega$.

 $V_{G2-S} = 4 \text{ V}; T_j = 25 \text{ }^{\circ}\text{C}.$

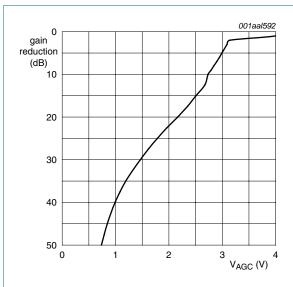


- (1) $V_{GG} = 5.0 \text{ V}.$
- (2) $V_{GG} = 4.5 \text{ V}.$
- (3) $V_{GG} = 4.0 \text{ V}.$
- (4) $V_{GG} = 3.5 \text{ V}.$
- (5) $V_{GG} = 3.0 \text{ V}.$

 T_{j} = 25 °C; R_{G1} = 39 $k\Omega$ (connected to V_{GG}).

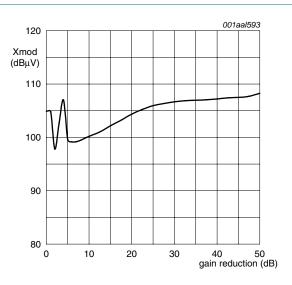
Drain current as a function of gate2 voltage; Fig 9. typical values

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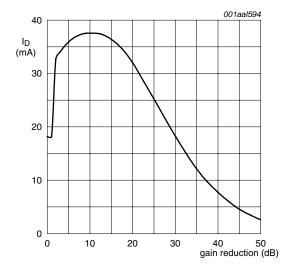
 $V_{DS}=5~V;~V_{GG}=5~V;~nominal~I_D=19~mA;~R_{G1}=39~k\Omega;\\f=50~MHz;~T_j=25~^{\circ}C;~see~\frac{Figure~17}{C}.$

Fig 10. Typical gain reduction as a function of the AGC voltage; typical values



$$\begin{split} V_{DS} = 5 \text{ V; } V_{GG} = 5 \text{ V; nominal } V_{G2\text{-S}} = 4 \text{ V; } R_{G1} = 39 \text{ k}\Omega; \\ f_w = 50 \text{ MHz; } f_{unw} = 60 \text{ MHz; nominal } I_D = 19 \text{ mA;} \\ T_j = 25 \text{ °C; see } \frac{Figure }{17}. \end{split}$$

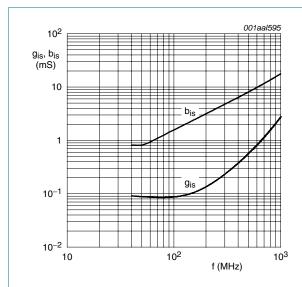
Fig 11. Unwanted voltage for 1 % cross modulation as a function of gain reduction; typical values



 $V_{DS} = 5 \text{ V}$; $V_{GG} = 5 \text{ V}$; nominal $V_{G2-S} = 4 \text{ V}$; $R_{G1} = 39 \text{ k}\Omega$; $f_w = 50 \text{ MHz}$; nominal $I_D = 19 \text{ mA}$; $T_i = 25 \text{ °C}$; see Figure 17.

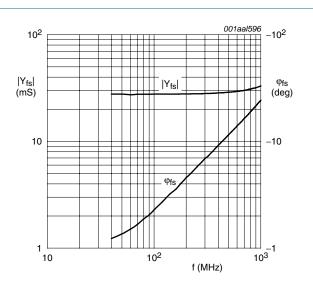
Fig 12. Typical drain current as a function of gain reduction; typical values

Dual N-channel dual gate MOSFET



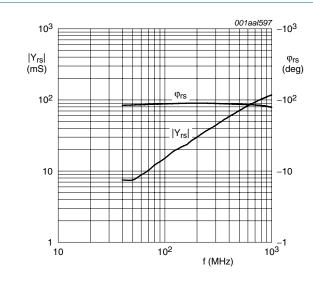
 $V_{DS(A)} = 5 \text{ V}; V_{G2-S} = 4 \text{ V}; V_{DS(B)} = 0 \text{ V}; I_{D(A)} = 19 \text{ mA};$

Fig 13. Input admittance as a function of frequency; typical values



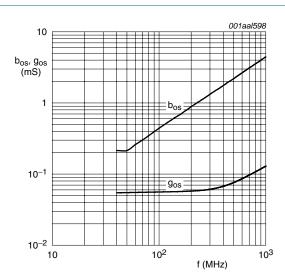
 $V_{DS(A)}=5$ V; $V_{G2\text{-}S}=4$ V; $V_{DS(B)}=0$ V; $I_{D(A)}=19$ mA; and vice versa.

Fig 14. Forward transfer admittance and phase as a function of frequency; typical values



 $V_{DS(A)}$ = 5 V; $V_{G2\text{-}S}$ = 4 V; $V_{DS(B)}$ = 0 V; $I_{D(A)}$ = 19 mA; and vice versa.

Fig 15. Reverse transfer admittance and phase as a function of frequency; typical values



 $V_{DS(A)}$ = 5 V; $V_{G2\text{-}S}$ = 4 V; $V_{DS(B)}$ = 0 V; $I_{D(A)}$ = 19 mA; and vice versa.

Fig 16. Output admittance as a function of frequency; typical values

Dual N-channel dual gate MOSFET

8.2 Scattering parameters for amplifiers A and B

Table 9. Scattering parameters for amplifiers A and B

 $V_{DS(A)} = 5 \text{ V; } V_{G2-S} = 4 \text{ V; } I_{D(A)} = 19 \text{ mA; } V_{DS(B)} = 0 \text{ V; } V_{G1-S(B)} = 0 \text{ V; } T_{amb} = 25 \text{ °C; } Z_0 = 50 \Omega; \text{ typical values.}$

f (MHz)	s ₁₁		s ₂₁	s ₂₁		s ₁₂		s ₂₂		
	Magnitude (ratio)	Angle (degree)	Magnitude (ratio)	Angle (degree)	Magnitude (ratio)	Angle (degree)	Magnitude (ratio)	Angle (degree)		
40	0.9910	-4.73	2.76	175.80	0.00074	99.46	0.9946	-1.29		
100	0.9888	-9.07	2.75	171.94	0.00150	86.12	0.9941	-2.65		
200	0.9853	-18.19	2.73	163.86	0.00292	79.56	0.9929	-5.31		
300	0.9762	-27.09	2.69	155.90	0.00420	74.12	0.9916	-7.92		
400	0.9656	-35.80	2.65	148.17	0.00540	69.71	0.9900	-10.49		
500	0.9502	-44.45	2.59	140.50	0.00634	65.32	0.9882	-13.05		
600	0.9331	-52.89	2.52	132.96	0.00709	61.01	0.9855	-15.66		
700	0.9155	-61.08	2.45	125.69	0.00751	57.66	0.9830	-18.24		
800	0.8966	-69.01	2.38	118.59	0.00782	54.58	0.9810	-20.75		
900	0.8755	-76.72	2.30	111.71	0.00792	52.37	0.9798	-23.19		
1000	0.8550	-84.10	2.22	105.07	0.00783	50.60	0.9785	-25.68		

8.3 Noise data for amplifiers A and B

Table 10. Noise data for amplifiers A and B

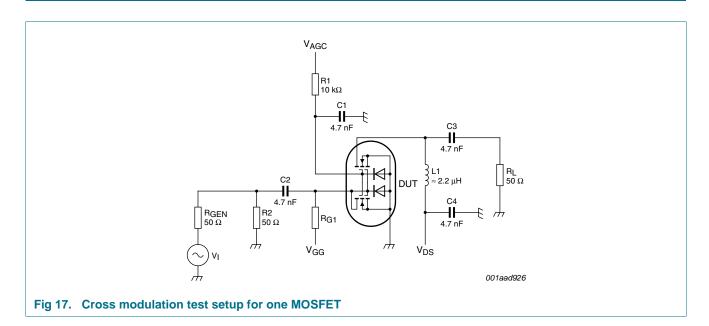
 $V_{DS(A)} = 5 \text{ V}$; $V_{G2-S} = 4 \text{ V}$; $I_{D(A)} = 19 \text{ mA}$, $T_{amb} = 25 ^{\circ}\text{C}$; typical values.

f (MHz)	NF _{min} (dB)	Γ_{opt}		r _n (ratio)
		(ratio)	(degree)	
400	1.0	0.788	28.9	0.903
800	1.5	0.673	58.8	0.725

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9. Test information



Dual N-channel dual gate MOSFET

10. Package outline

Plastic surface-mounted package; 6 leads

SOT363

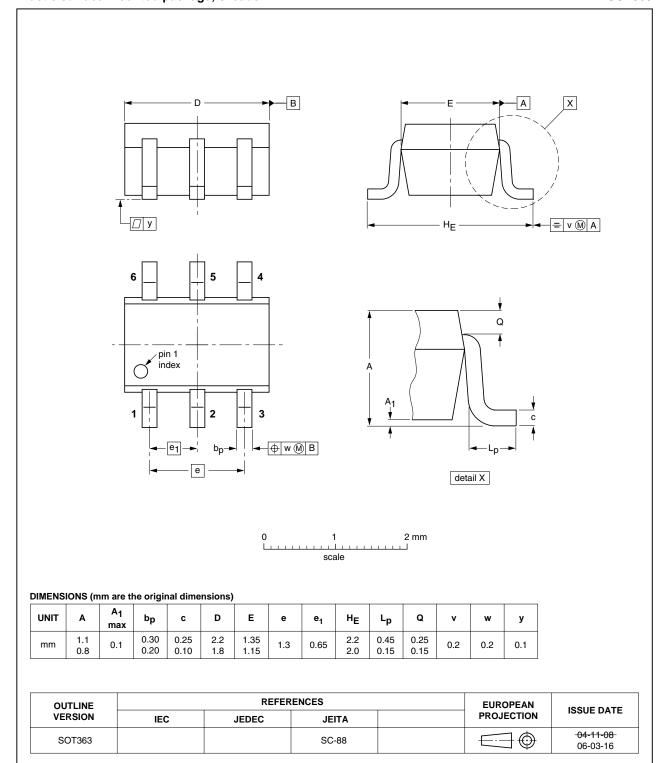


Fig 18. Package outline SOT363

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11. Abbreviations

Table 11. Abbreviations

Acronym	Description
AGC	Automatic Gain Control
MOSFET	Metal-Oxide Semiconductor Field-Effect Transistor
UHF	Ultra High Frequency
VHF	Very High Frequency

12. Revision history

Table 12. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BF1216_1	20100429	Product data sheet	-	-

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13. Legal information

13.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

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BF1216_1

Dual N-channel dual gate MOSFET

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BF1216 NXP Semiconductors

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15. Contents

1	Product profile	1
1.1	General description	1
1.2	Features and benefits	1
1.3	Applications	
1.4	Quick reference data	2
2	Pinning information	2
3	Ordering information	2
4	Marking	3
5	Limiting values	3
6	Thermal characteristics	4
7	Static characteristics	4
8	Dynamic characteristics	5
8.1	Graphs for amplifiers A and B	6
8.2	Scattering parameters for amplifiers A and B.	11
8.3	Noise data for amplifiers A and B	
9	Test information 1	12
10	Package outline	13
11	Abbreviations 1	14
12	Revision history 1	14
13	Legal information 1	15
13.1	Data sheet status	15
13.2	Definitions 1	15
13.3	Disclaimers	15
13.4	Trademarks1	16
14	Contact information 1	16
15	Contents	17

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